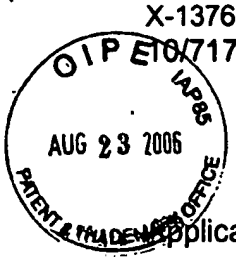
X-1376 US
10/717,359

PATENT
Conf. No.: 8181



IN THE UNITED STATES PATENT OFFICE

Applicant:	Sudip K. Nag		
Assignee:	Xilinx, Inc.		
Title:	Method and Apparatus for Timing Characterization of Integrated Circuit Designs		
Serial No.:	10/717,359	File Date:	11/18/2003
Examiner:	Vuthe Siek	Art Unit:	2825
Docket No.:	X-1376 US	Conf. No.:	8181

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RESPONSE TO FINAL OFFICE ACTION

716/6

Dear Sir:

In response to the Final Office Action mailed from the Patent Office on July 13, 2006, Applicant makes the following remarks.

OK to enter V.> 8/29/06

A listing of claims begins on page 2 of this paper.

Remarks begin on page 6 of this paper.